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Information Disclosure Statement Re: 10/737,038

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**Commissioner for Patents
Alexandria, VA 22313-1450**

ATTENTION EXAMINER: LUU, THANH X

on July 09, 2004

Return phone number 401-885-8032

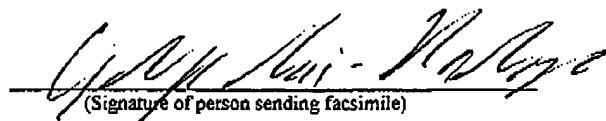
George Sai-Halasz Agent # 45430

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re application of: Min Yang

Serial No.: 10/737,038

Group No.: 2878

Filed: 12/16/2003

Examiner: LUU, THANH X

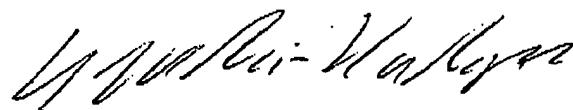
For: Photodetector with Hetero-structure Using Lateral Growth

Commissioner for Patents
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

The attached form 1449 (Modified) gives references pertaining to the above application.

Respectfully,



George Sai-Halasz Agent # 45430

Customer No.: 24,299

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07/09/2004

Sheet 1 of 1

Form PTO 1449 (modified)				Docket No <u>XOR920030313US1</u>	Serial No <u>10/737,938</u>		
LIST OF PRIOR ART CITED BY APPLICANT				Applicant <u>Min Yang</u>			
				Filing Date <u>12/16/2003</u>	Group <u>2878</u>		
U. S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
	AA	6,459,107	10/01/2002	Sugiyama	257	226	02/27/2001
	AB	6,451,702	09/17/2002	Yang	438	706	12/16/2001
	AC	6,043,517	03/28/2000	Presting	257	184	04/06/1998
	AD	5,994,724	11/30/1999	Morikawa	257	184	11/06/1997
FOREIGN PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
AA	"Avalanche Gain in Ge_xSi_{1-x}/Si Infrared Waveguide Detectors" Pearsall et al, IEEE Electron Device Letters, Vol EDL-7, No. 5., pp 330-332, (1986)						
Examiner				Date Considered			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant</small>							